Welcome to the Sixth Asian Test Symposium. This symposium is a forum for researchers and engineers from all countries of the world, especially from Asia, to explore the state-of-the-art and trends in test and design technologies for electronic circuits and systems.

This year we had a total of 88 regular paper submissions from Canada, China, France, Germany, Hong Kong, Italy, Israel, Japan, Korea, Lithuania, Malaysia, Poland, Russia, Singapore, Spain, Switzerland, Taiwan and USA. Moreover, special sessions on "Case Studies for DFT Techniques in Japanese Industry" and "Beam Testing Techniques in Japan" were proposed by Mr. Masaaki Yoshida, NEC Corporation, and Prof. Hiromu Fujioka, Osaka University, respectively. Eleven papers were submitted for those sessions. Each paper was sent to three reviewers for evaluation and paper selection was mostly based on the reviewers' ratings and comments. The final selection was made by the program committee, which met at Meiji University in Kawasaki on June 20, 1997. Then we produced a two-and-a-half day technical program consisting of 15 regular sessions and three special sessions.

A total of 55 papers are presented in the regular sessions which cover most of the key areas in testing, such as test generation, DFT, BIST, mixed-signal test, delay test, current test, diagnosis and FPGA test. Featured are the special sessions including 11 papers which properly introduce an aspect of present test technologies in Japan. In the plenary session, Dr. Vinod Agarwal, Logic Vision, gives the keynote address entitled "Embedded Test & Measurement is Critical for Deep Submicron Technology". I hope that ATS'97 will impress participants with the importance of this series of symposia and promote their future contributions.

Finally, I would like to thank Prof. Kozo Kinoshita, the Asian Activities Group Chair of IEEE Computer Society Test Technology Technical Committee, and Prof. Yuzo Takamatsu, the Symposium Chair, for their kind advice and support. Also, I would like to express my gratitude to the authors for submitting their works to ATS'97, and to the program committee members and the reviewers for their contribution and effort to produce an excellent technical program.

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